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April 2015

# FGD3325G2\_F085

# EcoSPARK®2 330mJ, 250V, N-Channel Ignition IGBT

### **Features**

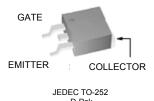
- SCIS Energy = 330mJ at T<sub>J</sub> = 25°C
- Logic Level Gate Drive
- Qualified to AEC Q101
- RoHS Compliant

### **Applications**

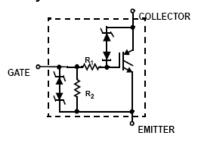
- Automotive Ignition Coil Driver Circuits
- Coil On Plug Applications



## Package



## Symbol



## **Absolute Maximum Ratings** $T_A = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		Ratings	Units
BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage (I <sub>C</sub> = 1mA)		250	V
BV <sub>ECS</sub>	Emitter to Collector Voltage - Reverse Battery Condition (I <sub>C</sub> = 10m	A)	28	V
E <sub>SCIS25</sub>	$I_{SCIS}$ = 14.8A, L = 3.0mHy, $R_{GE}$ = 1K $\Omega$	T <sub>C</sub> = 25°C	330	mJ
	$I_{SCIS}$ = 11.4A, L = 3.0mHy, $R_{GE}$ = 1K $\Omega$	T <sub>C</sub> = 150°C	195	mJ
I <sub>C25</sub>	Collector Current Continuous, at V <sub>GE</sub> = 5.0V, T <sub>C</sub> = 25°C		41	Α
I <sub>C110</sub>	Collector Current Continuous, at V <sub>GE</sub> = 5.0V, T <sub>C</sub> = 110°C		25	Α
$V_{GEM}$	Gate to Emitter Voltage Continuous		±10	V
D	Power Dissipation Total, at T <sub>C</sub> = 25°C	T <sub>C</sub> = 25°C	150	W
$P_D$	Power Dissipation Derating, for T <sub>C</sub> > 25°C	T <sub>C</sub> > 25°C	1.0	W/oC
T <sub>J</sub>	Operating Junction Temperature Range		-55 to +175	°C
T <sub>STG</sub>	Storage Junction Temperature Range		-55 to +175	°C
TL	Max. Lead Temp. for Soldering (Leads at 1.6mm from case for 10s	s)	300	°C
T <sub>PKG</sub>	Reflow soldering according to JESD020C		260	°C
ESD	HBM-Electrostatic Discharge Voltage at100pF, 1500Ω		4	kV
ESD	CDM-Electrostatic Discharge Voltage at $1\Omega$		2	kV

## Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FGD3325G2	FGD3325G2_F085	TO252	330mm	16mm	2500 units

## **Electrical Characteristics** $T_A = 25^{\circ}C$ unless otherwise noted

	Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
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#### **Off State Characteristics**

BV <sub>CER</sub>	Collector to Emitter Breakdown Voltage	$I_{CE} = 2mA, V_{GE} = 0,$ $R_{GE} = 1K\Omega,$ $T_{J} = -40 \text{ to } 150^{\circ}\text{C}$		225	-	275	٧
BV <sub>CES</sub>	Collector to Emitter Breakdown Voltage	$T_J = -40 \text{ to } 150^{\circ}\text{C}$		240	-	290	٧
BV <sub>ECS</sub>	Emitter to Collector Breakdown Voltage	$I_{CE}$ = -75mA, $V_{GE}$ = 0V, $T_{J}$ = 25°C		28	-	-	V
$BV_{GES}$	Gate to Emitter Breakdown Voltage	$I_{GES}$ = $\pm 2mA$		±12	±14	-	V
	Collector to Emitter Leakage Current	$V_{CE} = 175V, R_{GE} = 1K\Omega$	$T_J = 25^{\circ}C$	-	-	25	μА
I <sub>CER</sub>	Collector to Emitter Leakage Current		$T_{J} = 150^{\circ}C$	-	-	1	mA
	Emitter to Collector Lookage Current	V <sub>EC</sub> = 24V,	$T_{\rm J} = 25^{\rm o}{\rm C}$	-	-	1	A
I <sub>ECS</sub>	Emitter to Collector Leakage Current		$T_{J} = 150^{\circ}C$	-	-	40	mA
R <sub>1</sub>	Series Gate Resistance			-	120	-	Ω
R <sub>2</sub>	Gate to Emitter Resistance			10K	-	30K	Ω

#### **On State Characteristics**

V <sub>CE(SAT)</sub>	Collector to Emitter Saturation Voltage	$I_{CE} = 6A, V_{GE} = 4V,$	$T_J = 25^{\circ}C$	-	1.15	1.25	V
$V_{CE(SAT)}$	Collector to Emitter Saturation Voltage	$I_{CE}$ = 10A, $V_{GE}$ = 4.5V,	$T_{\rm J} = 150^{\rm o}{\rm C}$	-	1.35	1.50	V
$V_{CE(SAT)}$	Collector to Emitter Saturation Voltage	$I_{CE} = 15A, V_{GE} = 4.5V,$	$T_{\rm J} = 150^{\rm o}{\rm C}$	ı	1.68	1.85	V

# **Electrical Characteristics** $T_A = 25^{\circ}C$ unless otherwise noted

Parameter

Dynam	Dynamic Characteristics							
Q <sub>G(ON)</sub>	Gate Charge	I <sub>CE</sub> = 10A, V <sub>CE</sub> = 12V, V <sub>GE</sub> = 5V		-	21	-	nC	
V <sub>GE(TH)</sub>	Gate to Emitter Threshold Voltage	I <sub>CE</sub> = 1mA, V <sub>CE</sub> = V <sub>GE</sub> .	$T_{J} = 25^{\circ}C$	1.3	1.5	2.2	V	
VGE(TH)	Gate to Emitter Threshold Voltage	I'CE - IIIIA, VCE - VGE,	$T_{\rm J} = 150^{\rm o}{\rm C}$	0.75	1.1	1.8	v	
$V_{GEP}$	Gate to Emitter Plateau Voltage	V <sub>CE</sub> = 12V, I <sub>CE</sub> = 10A		-	2.7	-	V	

**Test Conditions** 

Min

Max Units

#### **Switching Characteristics**

Symbol

$t_{d(ON)R}$	Current Turn-On Delay Time-Resistive		-	8.0	4	μS
$t_{rR}$	Current Rise Time-Resistive	$V_{GE}$ = 5V, $R_G$ = 1K $\Omega$ T <sub>J</sub> = 25°C,	-	1.2	7	μS
t <sub>d(OFF)L</sub>	Current Turn-Off Delay Time-Inductive	OL , ,	-	5.1	15	μS
t <sub>fL</sub>	Current Fall Time-Inductive	$V_{GE} = 5V, R_{G} = 1K\Omega$ $I_{CE} = 6.5A, T_{J} = 25^{\circ}C,$	-	2.2	15	μS

#### **Thermal Characteristics**

R <sub>θJC</sub> Thermal Resistance Junction to Case	-	-	1	°C/W	
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### **Typical Performance Curves**

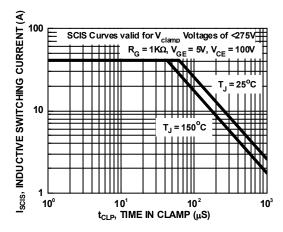


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp

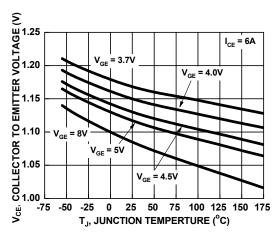


Figure 3. Collector to Emitter On-State Voltage vs. Junction Temperature

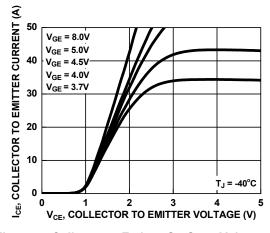


Figure 5. Collector to Emitter On-State Voltage vs. Collector Current

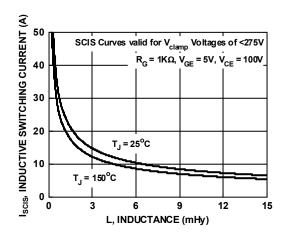


Figure 2. Self Clamped Inductive Switching Current vs. Inductance

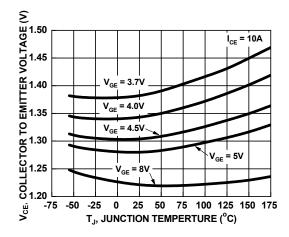


Figure 4. Collector to Emitter On-State Voltage vs. Junction Temperature

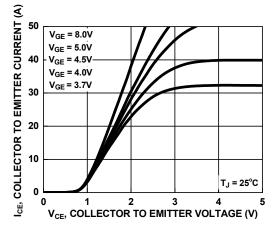


Figure 6. Collector to Emitter On-State Voltage vs. Collector Current

### Typical Performance Curves (Continued)

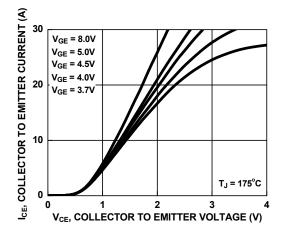


Figure 7. Collector to Emitter On-State Voltage vs. Collector Current

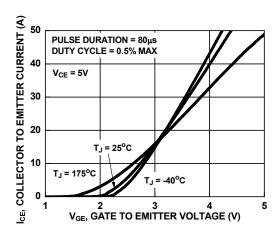


Figure 8. Transfer Characteristics

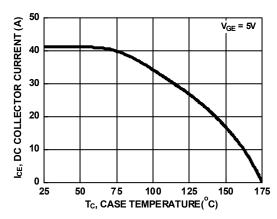


Figure 9. DC Collector Current vs. Case Temperature

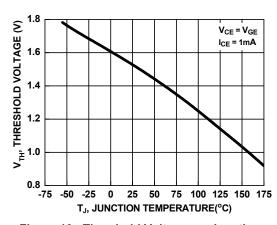


Figure 10. Threshold Voltage vs. Junction Temperature

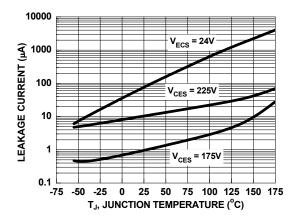


Figure 11. Leakage Current vs. Junction Temperature

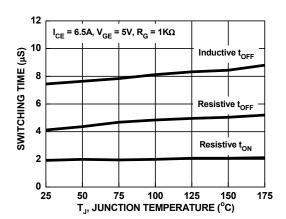


Figure 12. Switching Time vs. Junction Temperature

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**Typical Performance Curves** (Continued)

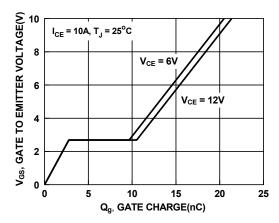


Figure 13. Capacitance vs. Collector to Emitter Voltage

10

15

V<sub>DS</sub>, DRAIN TO SOURCE VOLTAGE (V)

20

Figure 14. Gate Charge

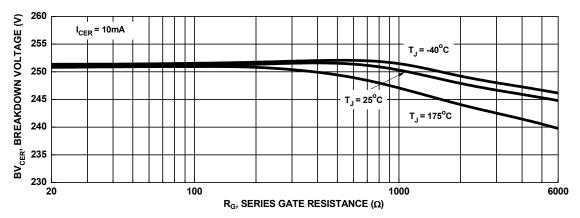


Figure 15. Break down Voltage vs. Series Gate Resistance

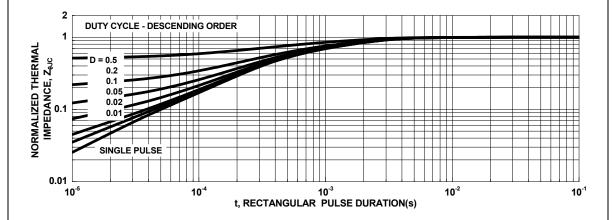


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

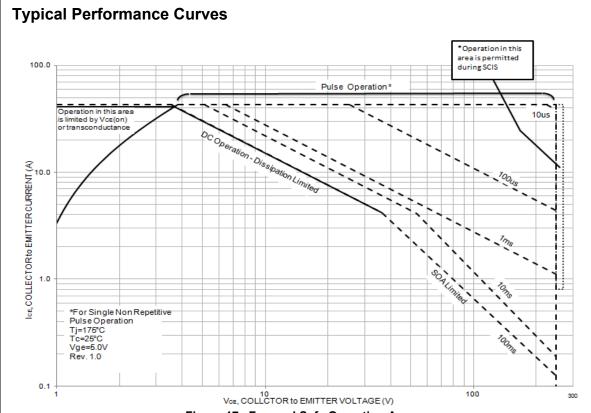


Figure 17. Forward Safe Operating Area

## **Test Circuit and Waveforms**

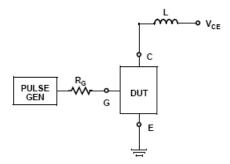


Figure 17. Inductive Switching Test Circuit

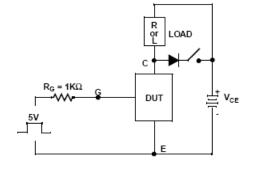


Figure 18.  $t_{ON}$  and  $t_{OFF}$  Switching Test Circuit

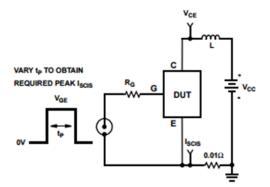


Figure 19. Energy Test Circuit

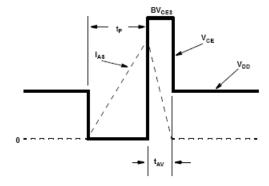
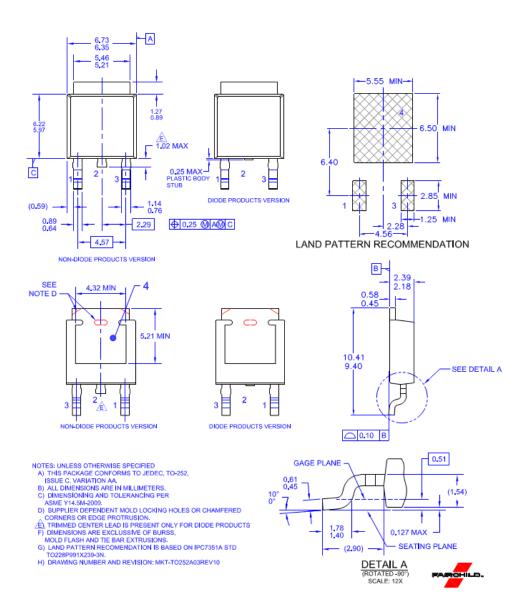


Figure 20. Energy Waveforms

### **Mechanical Dimensions**

## **D-PAK**



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